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TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor
SCHS187C

January 1998 - Revised July 2003

CD54/74HC533, CD54/74HCT533, CD54/74HC563, CD74HCT563

High-Speed CMOS Logic Octal Inverting Transparent Latch, Three-State Outputs

Features

- **Common Latch-Enable Control**
- **Common Three-State Output Enable Control**
- **Buffered Inputs**
- **Three-State Outputs**
- **Bus Line Driving Capacity**
- **Typical Propagation Delay = 13ns at V_{CC} = 5V, C_L = 15pF, T_A = 25°C (Data to Output)**
- **Fanout (Over Temperature Range)**
  - **Standard Outputs . . . . 10 LSTTL Loads**
  - **Bus Driver Outputs . . . . 15 LSTTL Loads**
- **Wide Operating Temperature Range . . . -55°C to 125°C**
- **Balanced Propagation Delay and Transition Times**
- **Significant Power Reduction Compared to LSTTL Logic ICs**
- **HC Types**
  - **2V to 6V Operation**
  - **High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V**
- **HCT Types**
  - **4.5V to 5.5V Operation**
  - **Direct LSTTL Input Logic Compatibility, V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)**
  - **CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL}, V_{OH}**

Description

The 'HC533, 'HCT533, 'HC563, and CD74HCT563 are high-speed Octal Transparent Latches manufactured with silicon gate CMOS technology. They possess the low power consumption of standard CMOS integrated circuits, as well as the ability to drive 15 LSTTL devices.

The outputs are transparent to the inputs when the latch enable ($\overline{LE}$) is high. When the latch enable ($\overline{LE}$) goes low the data is latched. The output enable ($\overline{OE}$) controls the three-state outputs. When the output enable ($\overline{OE}$) is high the outputs are in the high impedance state. The latch operation is independent of the state of the output enable.
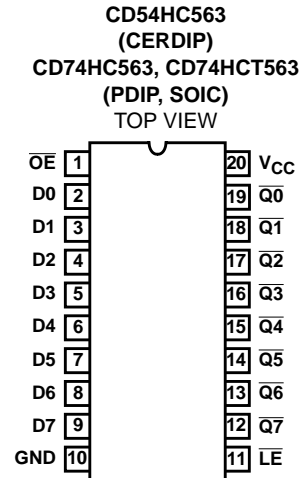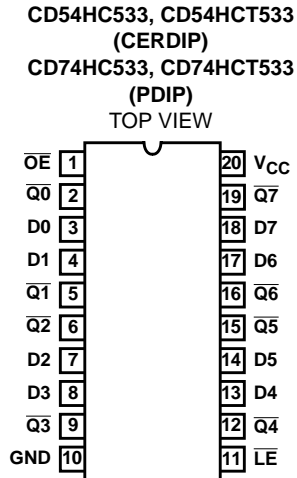
The 'HC533 and 'HCT533 are identical in function to the 'HC563 and CD74HCT563 but have different pinouts. The 'HC533 and 'HCT533 are similar to the 'HC373 and 'HCT373; the latter are non-inverting types.
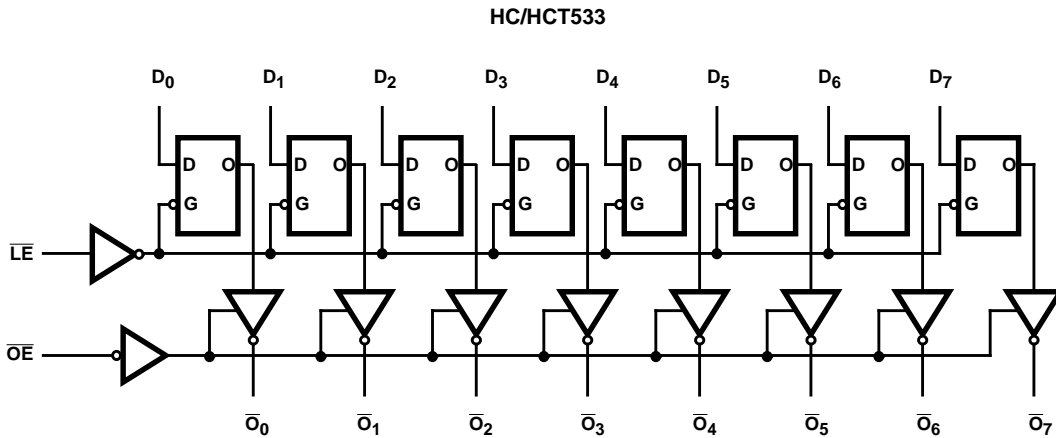
Ordering Information

PART NUMBER	TEMP. RANGE (^{o}C)	PACKAGE
CD54HC533F3A	-55 to 125	20 Ld CERDIP
CD54HC563F3A	-55 to 125	20 Ld CERDIP
CD54HCT533F3A	-55 to 125	20 Ld CERDIP
CD74HC533E	-55 to 125	20 Ld PDIP
CD74HC563E	-55 to 125	20 Ld PDIP
CD74HC563M	-55 to 125	20 Ld SOIC
CD74HCT533E	-55 to 125	20 Ld PDIP
CD74HCT563E	-55 to 125	20 Ld PDIP
CD74HCT563M	-55 to 125	20 Ld SOIC

Pinouts

**CD54HC533, CD54HCT533
(CERDIP)
CD74HC533, CD74HCT533
(PDIP)**
TOP VIEW

$\overline{OE}$	1	20	V_{CC}
$\overline{Q0}$	2	19	$\overline{Q7}$
D0	3	18	D7
D1	4	17	D6
$\overline{Q1}$	5	16	$\overline{Q6}$
$\overline{Q2}$	6	15	$\overline{Q5}$
D2	7	14	D5
D3	8	13	D4
$\overline{Q3}$	9	12	$\overline{Q4}$
GND	10	11	$\overline{LE}$

**CD54HC563
(CERDIP)
CD74HC563, CD74HCT563
(PDIP, SOIC)**
TOP VIEW

$\overline{OE}$	1	20	V_{CC}
D0	2	19	$\overline{Q0}$
D1	3	18	$\overline{Q1}$
D2	4	17	$\overline{Q2}$
D3	5	16	$\overline{Q3}$
D4	6	15	$\overline{Q4}$
D5	7	14	$\overline{Q5}$
D6	8	13	$\overline{Q6}$
D7	9	12	$\overline{Q7}$
GND	10	11	$\overline{LE}$

Functional Block Diagram

HC/HCT533

TRUTH TABLE

$\overline{\text{OUTPUT ENABLE}}$	$\overline{\text{LATCH ENABLE}}$	DATA	Q OUTPUT
L	H	H	L
L	H	L	H
L	L	I	H
L	L	h	L
H	X	X	Z

H = High Voltage Level, L = Low Voltage Level, X = Don't Care, Z = High Impedance State, I = Low voltage level one set-up time prior to the high to low latch enable transition, h = High voltage level one set-up time prior to the high to low latch enable transition.

CD54/74HC533, CD54/74HCT533, CD54/74HC563, CD74HCT563

Absolute Maximum Ratings

DC Supply Voltage, V_{CC} . . . . -0.5V to 7V
DC Input Diode Current, I_{IK}
  For V_I < -0.5V or V_I > V_{CC} + 0.5V . . . . ±20mA
DC Output Diode Current, I_{OK}
  For V_O < -0.5V or V_O > V_{CC} + 0.5V . . . . ±20mA
DC Drain Current, per Output, I_O
  For -0.5V < V_O < V_{CC} + 0.5V . . . . ±35mA
DC Output Source or Sink Current per Output Pin, I_O
  For V_O > -0.5V or V_O < V_{CC} + 0.5V . . . . ±25mA
DC V_{CC} or Ground Current, I_{CC} . . . . ±50mA

Operating Conditions

Temperature Range, T_A . . . . -55°C to 125°C
Supply Voltage Range, V_{CC}
  HC Types . . . . .2V to 6V
  HCT Types . . . . .4.5V to 5.5V
DC Input or Output Voltage, V_I, V_O . . . . 0V to V_{CC}
Input Rise and Fall Time
  2V . . . . 1000ns (Max)
  4.5V. . . . . 500ns (Max)
  6V . . . . 400ns (Max)

Thermal Information

Thermal Resistance (Typical, Note 1) θ_{JA} (°C/W)
  E (PDIP) Package 69
  M (SOIC) Package. 58
Maximum Junction Temperature . . . . 150°C
Maximum Storage Temperature Range . . . . -65°C to 150°C
Maximum Lead Temperature (Soldering 10s) . . . . 300°C
  (SOIC - Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. The package thermal impedance is calculated in accordance with JESD 51-7.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS V_I (V)	I_O (mA)	V_{CC} (V)	25°C MIN	TYP	MAX	-40°C TO 85°C MIN	MAX	-55°C TO 125°C MIN	MAX	UNITS
HC TYPES												
High Level Input Voltage	V_{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input Voltage	V_{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V
				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V
			-7.8	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V
			7.8	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	-	-	8	-	80	-	160	µA

DC Electrical Specifications   (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Three-State Leakage Current	-	V_{IL} or V_{IH}	V_O = V_{CC} or GND	6	-	-	±0.5	-	±5	-	±10	µA
HCT TYPES												
High Level Input Voltage	V_{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V_{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} to GND	-	5.5	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	5.5	-	-	8	-	80	-	160	µA
Three-State Leakage Current	-	V_{IL} or V_{IH}	V_O = V_{CC} or GND	5.5	-	-	±0.5	-	±5	-	±10	µA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI_{CC} (Note 2)	V_{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	µA

NOTE:

2. For dual-supply systems theoretical worst case (V_I = 2.4V, V_{CC} = 5.5V) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS
D0 - D7	0.15
$\overline{LE}$	0.30
$\overline{OE}$	0.55

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Specifications table, e.g., 360µA max at 25°C.

Prerequisite For Switching Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C MIN	25°C TYP	25°C MAX	-40°C TO 85°C MIN	-40°C TO 85°C MAX	-55°C TO 125°C MIN	-55°C TO 125°C MAX	UNITS
HC TYPES											
$\overline{LE}$ Pulse Width	t_W	-	2	80	-	-	100	-	120	-	ns
			4.5	16	-	-	20	-	24	-	ns
			6	14	-	-	17	-	20	-	ns
Set-up Time Data to $\overline{LE}$	t_{SU}	-	2	50	-	-	65	-	75	-	ns
			4.5	10	-	-	13	-	15	-	ns
			6	9	-	-	11	-	13	-	ns
Hold Time, Data to $\overline{LE}$ (533)	t_H	-	2	35	-	-	45	-	55	-	ns
			4.5	7	-	-	9	-	11	-	ns
			6	6	-	-	8	-	7	-	ns
Hold Time, Data to $\overline{LE}$ (563)	t_H	-	2	4	-	-	4	-	4	-	ns
			4.5	4	-	-	4	-	4	-	ns
			6	4	-	-	4	-	4	-	ns
HCT TYPES											
$\overline{LE}$ Pulse Width	t_W	-	4.5	16	-	-	20	-	24	-	ns
Set-up Time Data to $\overline{LE}$	t_W	-	4.5	10	-	-	13	-	15	-	ns
Hold Time, Data to $\overline{LE}$ (533)	t_H	-	4.5	8	-	-	10	-	12	-	ns
Hold Time, Data to $\overline{LE}$ (563)	t_H	-	4.5	5	-	-	5	-	5	-	ns

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C TYP	25°C MAX	-40°C TO 85°C MAX	-55°C TO 125°C MAX	UNITS
HC TYPES								
Propagation Delay, Data to Qn (HC533)	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	165	205	250	ns
			4.5	-	33	41	50	ns
			6	-	28	35	43	ns
		C_L = 15pF	5	13	-	-	-	ns
Propagation Delay, Data to Qn (HC563)	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C_L = 15pF	5	12	-	-	-	ns
Propagation Delay, $\overline{LE}$ to Qn (HC533)	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	175	220	265	ns
			4.5	-	35	44	53	ns
			6	-	30	37	45	ns
		C_L = 15pF	5	14	-	-	-	ns
Propagation Delay, $\overline{LE}$ to Qn (HC563)	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	165	205	250	ns
			4.5	-	33	41	50	ns
			6	-	28	35	43	ns
		C_L = 15pF	5	13	-	-	-	ns

# CD54/74HC533, CD54/74HCT533, CD54/74HC563, CD74HCT563

Switching Specifications Input t_r, t_f = 6ns (Continued)

| PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C TYP	25°C MAX	-40°C TO 85°C MAX	-55°C TO 125°C MAX	UNITS
Enable Times (HC533)	t_{PZH}, t_{PZL}	C_L = 50pF	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C_L = 15pF	5	12	-	-	-	ns
Disable Times (HC533)	t_{PHZ}, t_{PLZ}	C_L = 50pF	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C_L = 15pF	5	12	-	-	-	ns
Enable and Disable Times (HC563)	t_{PZH}, t_{PZL}, t_{PHZ}, t_{PLZ}	C_L = 50pF	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C_L = 15pF	5	12	-	-	-	ns
Input Capacitance	C_I	-	-	-	10	10	10	pF
Three-State Output Capacitance	C_O	-	-	-	20	20	20	pF
Power Dissipation Capacitance (Notes 3, 4)	C_{PD}	-	5	42	-	-	-	pF
HCT TYPES								
Propagation Delay, Data to Qn (HC/HCT533)	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	34	43	51	ns
		C_L = 15pF	5	14	-	-	-	ns
Propagation Delay, Data to Qn (HC/HCT563)	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	30	38	45	ns
		C_L = 15pF	5	12	-	-	-	ns
Propagation Delay, $\overline{LE}$ to Qn (HC/HCT533)	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	-	38	48	57	ns
		C_L = 15pF	5	16	-	-	-	ns
Propagation Delay, $\overline{LE}$ to Qn (HC/HCT563)	t_{PZL}, t_{PZH}	C_L = 50pF	4.5	-	35	44	53	ns
		C_L = 15pF	5	14	-	-	-	ns
Enable Times (HC/HCT533)	t_{PLZ}, t_{PZH}	C_L = 50pF	4.5	-	35	44	53	ns
		C_L = 15pF	5	14	-	-	-	ns
Disable Times (HC/HCT533)	t_{TLH}, t_{THL}	C_L = 50pF	4.5	-	30	38	45	ns
		C_L = 15pF	5	12	-	-	-	ns
Enable and Disable Times (HC/HCT563)	t_{PZH}, t_{PZL}, t_{PHZ}, t_{PLZ}	C_L = 50pF	4.5	-	35	44	53	ns
		C_L = 15pF	5	14	-	-	-	ns
Input Capacitance	C_I	-	-	-	10	10	10	pF
Power Dissipation Capacitance (Notes 3, 4)	C_{PD}	-	5	42	-	-	-	pF

NOTES:

3. C_{PD} is used to determine the no-load dynamic power consumption, per latch.

4. P_D (total power per latch) = $C_{PD} V_{CC}^2 f_i + \Sigma C_L V_{CC}^2 f_o$ where f_i = Input Frequency, f_o = Output Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuits and Waveforms
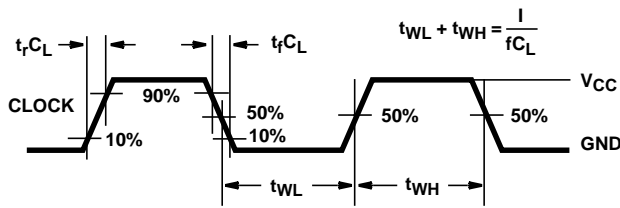
NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX}, input duty cycle = 50%.

FIGURE 1. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH
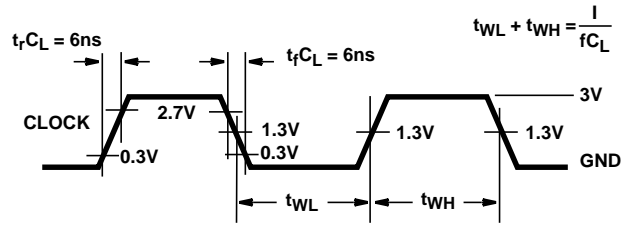
NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX}, input duty cycle = 50%.

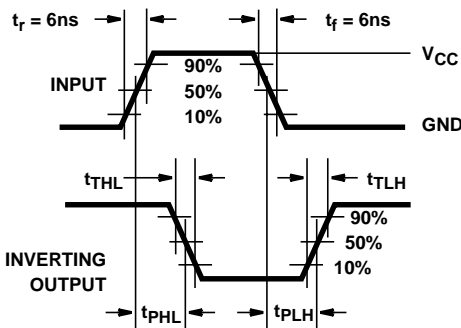**FIGURE 2. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH**

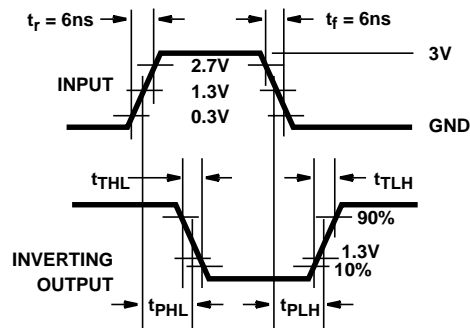**FIGURE 3. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC**

FIGURE 4. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC
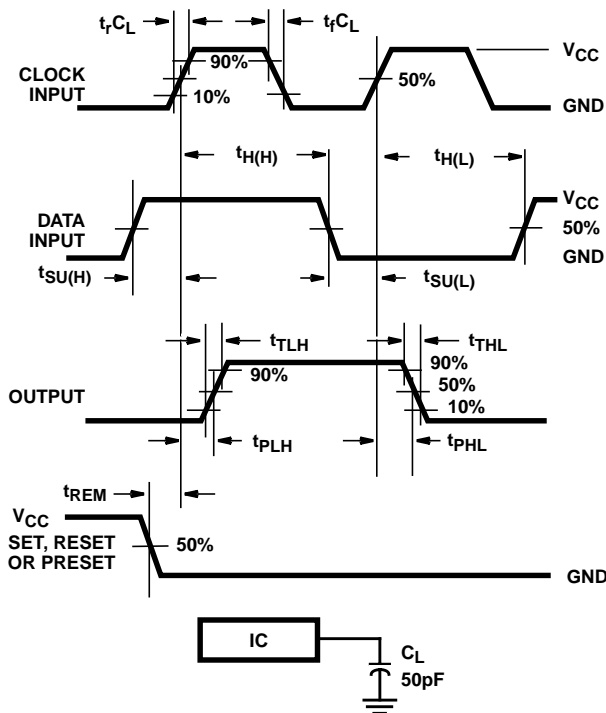
FIGURE 5. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS
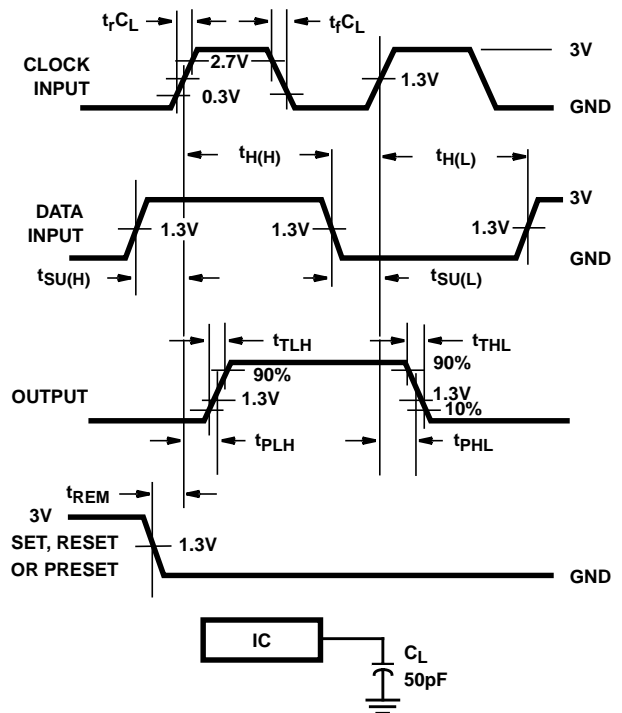
FIGURE 6. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

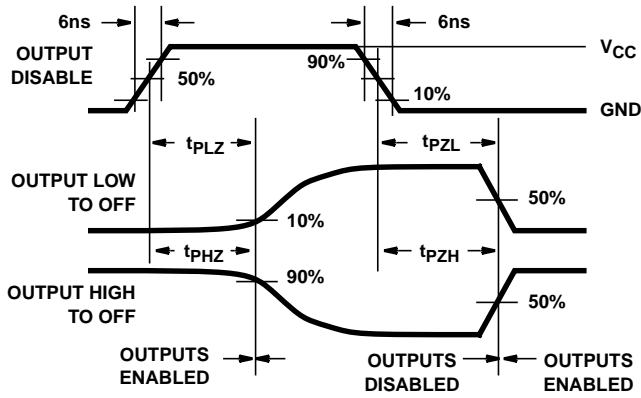## *Test Circuits and Waveforms* (Continued)

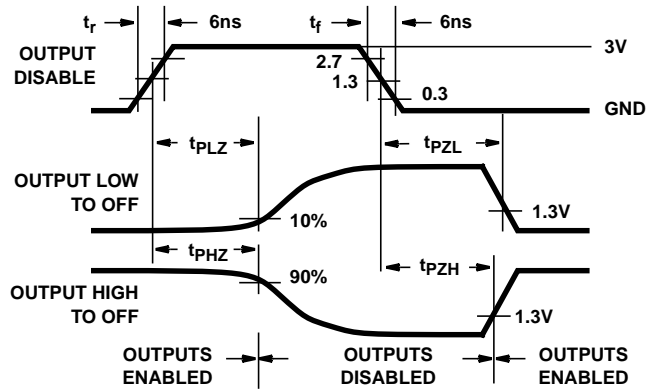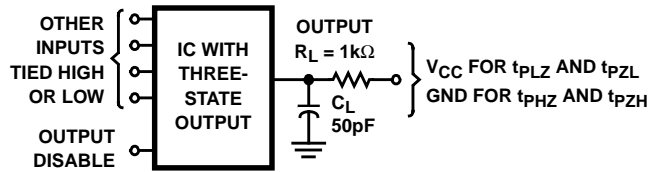**FIGURE 7. HC THREE-STATE PROPAGATION DELAY WAVEFORM**

FIGURE 8. HCT THREE-STATE PROPAGATION DELAY WAVEFORM

NOTE: Open drain waveforms t_{PLZ} and t_{PZL} are the same as those for three-state shown on the left. The test circuit is Output R_L = 1kΩ to V_{CC}, C_L = 50pF.

FIGURE 9. HC AND HCT THREE-STATE PROPAGATION DELAY TEST CIRCUIT

PACKAGE OPTION ADDENDUM

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
5962-8606201RA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8606201RA CD54HC563F3A	Samples
5962-8681301RA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8681301RA CD54HC533F3A	Samples
CD54HC533F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8681301RA CD54HC533F3A	Samples
CD54HC563F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8606201RA CD54HC563F3A	Samples
CD54HCT533F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD54HCT533F3A	Samples
CD74HC533E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC533E	Samples
CD74HC533EE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC533E	Samples
CD74HC563E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC563E	Samples
CD74HC563EE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC563E	Samples
CD74HCT533E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT533E	Samples
CD74HCT533EE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT533E	Samples
CD74HCT563E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT563E	Samples
CD74HCT563EE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT563E	Samples
CD74HCT563M	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT563M	Samples
CD74HCT563ME4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT563M	Samples
CD74HCT563MG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT563M	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

[2] Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

[3] MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

[4] There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

[5] Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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OTHER QUALIFIED VERSIONS OF CD54HC533, CD54HC563, CD54HCT533, CD74HC533, CD74HC563, CD74HCT533 :

● Catalog: CD74HC533, CD74HC563, CD74HCT533

● Military: CD54HC533, CD54HC563, CD54HCT533

NOTE: Qualified Version Definitions:

   ● Catalog - TI's standard catalog product

• Military - QML certified for Military and Defense Applications

J (R—GDIP—T**)　　　　　　　　CERAMIC DUAL IN—LINE PACKAGE

14 LEADS SHOWN

DIM \ PINS **	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	——	——	——	——
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)

B

14　　　8

C

1　　　7

0.065 (1,65)
0.045 (1,14)

0.005 (0,13) MIN

0.060 (1,52)
0.015 (0,38)

0.200 (5,08) MAX

Seating Plane

0.130 (3,30) MIN

0.026 (0,66)
0.014 (0,36)

0.100 (2,54)

A

0°–15°

0.014 (0,36)
0.008 (0,20)

4040083/F 03/03
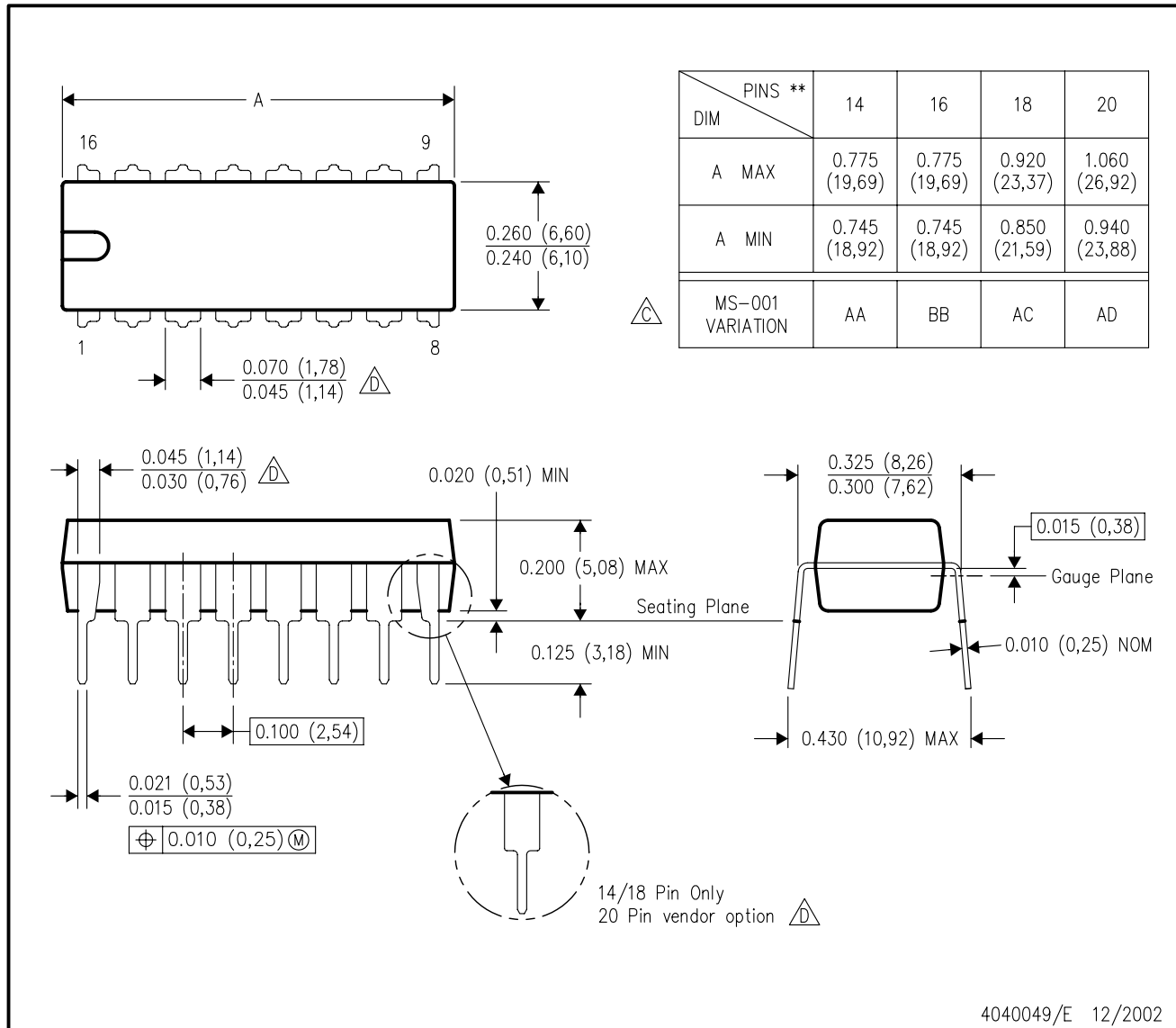
NOTES:　A.　All linear dimensions are in inches (millimeters).
　　　　　B.　This drawing is subject to change without notice.
　　　　　C.　This package is hermetically sealed with a ceramic lid using glass frit.
　　　　　D.　Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
　　　　　E.　Falls within MIL STD 1835 GDIP1–T14, GDIP1–T16, GDIP1–T18 and GDIP1–T20.

N (R−PDIP−T**)

PLASTIC DUAL−IN−LINE PACKAGE

16 PINS SHOWN

DIM \ PINS **	14	16	18	20
A MAX	0.775 (19,69)	0.775 (19,69)	0.920 (23,37)	1.060 (26,92)
A MIN	0.745 (18,92)	0.745 (18,92)	0.850 (21,59)	0.940 (23,88)
MS−001 VARIATION	AA	BB	AC	AD

0.260 (6,60)
0.240 (6,10)

0.070 (1,78)
0.045 (1,14) ⚠D

0.045 (1,14)
0.030 (0,76) ⚠D

0.020 (0,51) MIN

0.200 (5,08) MAX

Seating Plane

0.125 (3,18) MIN

0.100 (2,54)

0.021 (0,53)
0.015 (0,38)

⊕ 0.010 (0,25) Ⓜ

14/18 Pin Only
20 Pin vendor option ⚠D

0.325 (8,26)
0.300 (7,62)

0.015 (0,38)

Gauge Plane

0.010 (0,25) NOM

0.430 (10,92) MAX

4040049/E   12/2002
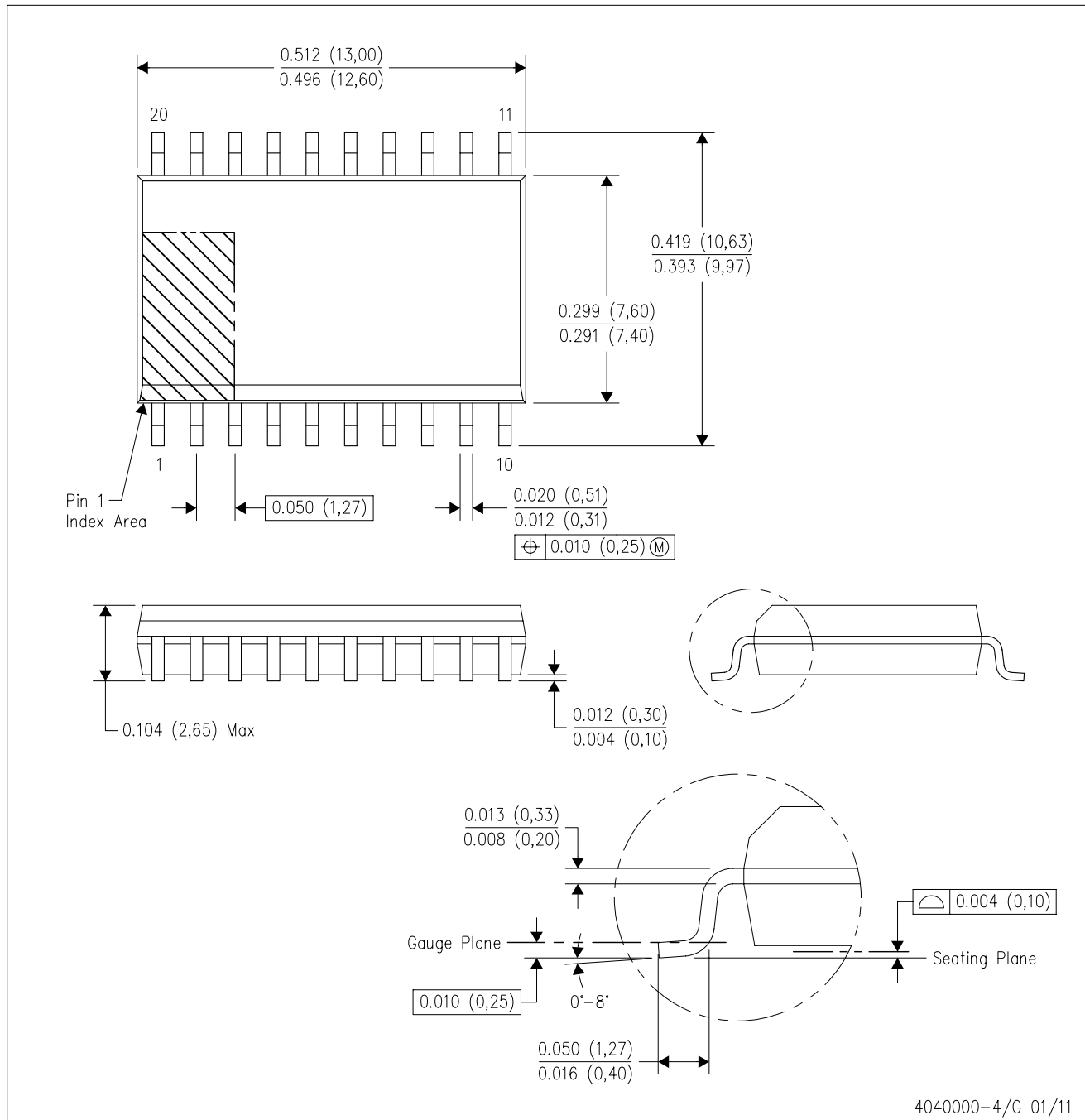
NOTES: A. All linear dimensions are in inches (millimeters).
         B. This drawing is subject to change without notice.
       ⚠C Falls within JEDEC MS−001, except 18 and 20 pin minimum body length (Dim A).
       ⚠D The 20 pin end lead shoulder width is a vendor option, either half or full width.
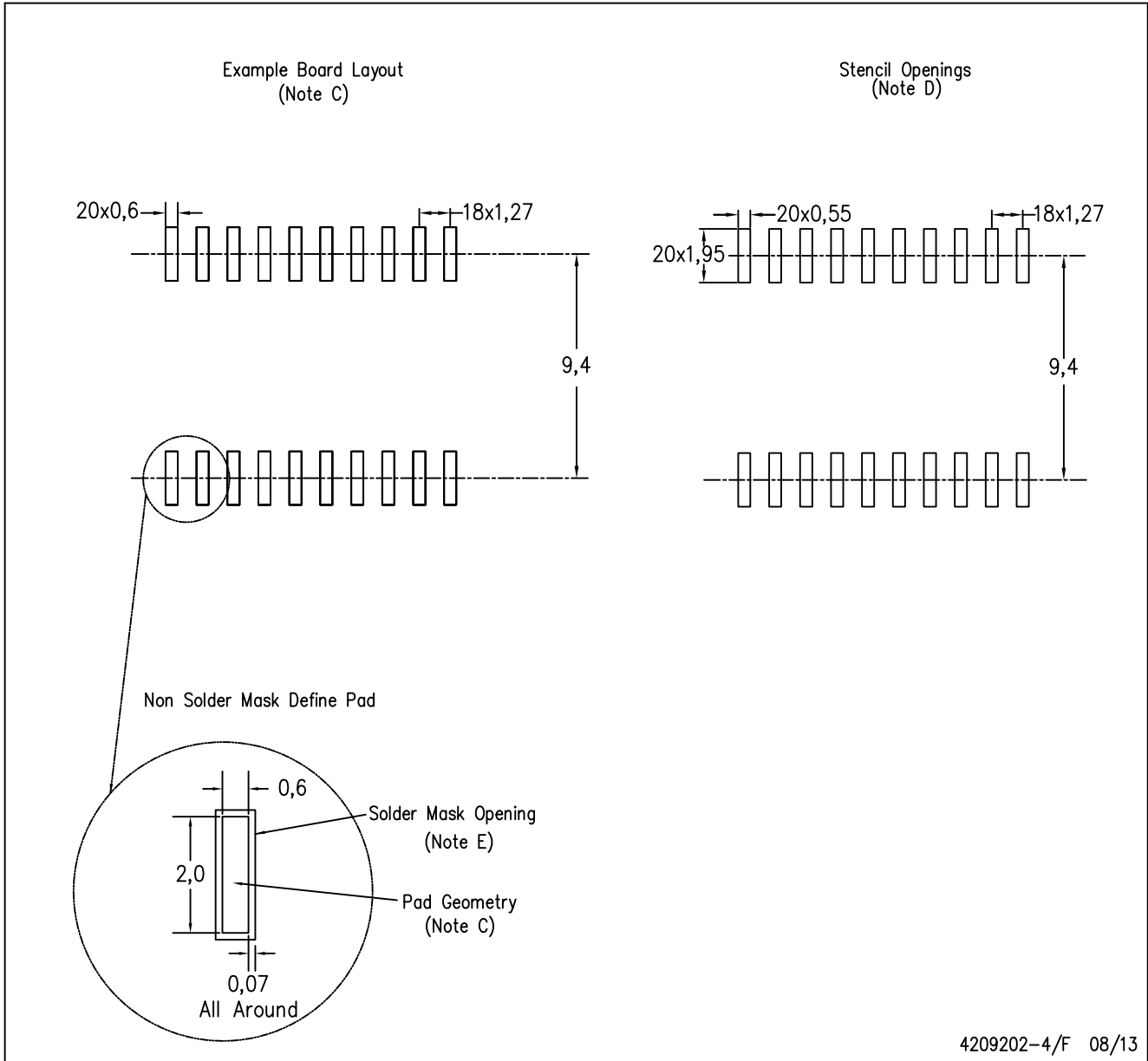
DW (R−PDSO−G20)   PLASTIC SMALL OUTLINE

$\dfrac{0.512\ (13,00)}{0.496\ (12,60)}$

20   11

$\dfrac{0.419\ (10,63)}{0.393\ (9,97)}$

$\dfrac{0.299\ (7,60)}{0.291\ (7,40)}$

1   10

Pin 1
Index Area

0.050 (1,27)

$\dfrac{0.020\ (0,51)}{0.012\ (0,31)}$

⊕ | 0.010 (0,25) Ⓜ

0.104 (2,65) Max

$\dfrac{0.012\ (0,30)}{0.004\ (0,10)}$

$\dfrac{0.013\ (0,33)}{0.008\ (0,20)}$

◯ 0.004 (0,10)

Gauge Plane

Seating Plane

0.010 (0,25)

0°−8°

$\dfrac{0.050\ (1,27)}{0.016\ (0,40)}$

4040000−4/G 01/11

NOTES: A.   All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M−1994.
         B.   This drawing is subject to change without notice.
         C.   Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
         D.   Falls within JEDEC MS−013 variation AC.

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DW (R−PDSO−G20)   PLASTIC SMALL OUTLINE

Example Board Layout
(Note C)

Stencil Openings
(Note D)

20x0,6

18x1,27

9,4

20x0,55

18x1,27

20x1,95

9,4

Non Solder Mask Define Pad

0,6

Solder Mask Opening
(Note E)

2,0

Pad Geometry
(Note C)

0,07
All Around

4209202−4/F   08/13

NOTES: A.   All linear dimensions are in millimeters.
         B.   This drawing is subject to change without notice.
         C.   Refer to IPC7351 for alternate board design.
         D.   Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should
              contact their board assembly site for stencil design recommendations. Refer to IPC−7525
         E.   Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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